



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No.10/632,273
Filing Date July 31, 2003
Inventor Warren M. Farnworth, et al.
Assignee Micron Technology, Inc.
Group Art Unit 2829
Examiner Russell M. Kobert
Attorney's Docket No. MI22-2379
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and
Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

RESPONSE TO MAY 9, 2006 OFFICE ACTION

To: Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

From: D. Brent Kenady
Tel. 509-624-4276; Fax 509-838-3424
Wells St. John P.S.
601 West First Avenue, Suite 1300
Spokane, WA 99201-3828

Sir:

Responsive to the Office Action dated May 9, 2006, Applicant amends and remarks
as follows:

AMENDMENTS

Underlines indicate insertions and ~~strikeouts~~ indicate deletions.

09/14/2006 RMEBRAHT 00000068 10632273

02 FC:1202 250.00 OP
03 FC:1201 200.00 OP